P-type Cu<sub>7</sub>Te<sub>5</sub> Single-crystalline Nanocuboids: Size-Controlled Synthesis and Their Large-scale Self-assembly

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## **Supporting Information:**



Figure S1 Large-scale TEM images of as-prepared Cu<sub>7</sub>Te<sub>5</sub> nanocuboids.



Figure S2 TEM image of large-scale self-assembly.



Figure S3 STEM image of large-scale micrometer sized superstructures composed by nanocube-liked nanocuboids.

The analysis of the largest exposed faces of the crystal:

As shown in Fig. 1, for the  $Cu_7Te_5$  nanocuboids, the distance measured between two adjacent fringes is 0.70 nm and 0.52 nm, which is the interfacial spacing of the orthorhombic  $Cu_7Te_5$  (0 0 2) and (0 3 2), and the corresponding fast Fourier transform (FFT) pattern contains the diffraction spots from the (0 3 2) and (0 3 0) planes of orthorhombic phase  $Cu_7Te_5$ .

According to Zone law, the following equation exists between the zone axis [u v w] and the indices of crystal face (h k l) belongs to the zone axis<sup>1</sup>

$$hu + kv + lw = 0$$

So, if we know two planes  $(h_1 k_1 l_1)$  and  $(h_2 k_2 l_2)$  which did not parallel, we can get the zone axis by using the following equation:

$$u:v:w = \begin{bmatrix} k1 & l1\\ k2 & l2 \end{bmatrix}: \begin{bmatrix} l1 & h1\\ l2 & h2 \end{bmatrix}: \begin{bmatrix} h1 & k1\\ h2 & k2 \end{bmatrix}$$

So according to plane (0 3 2) and plane (0 3 0), we can calculate the zone axis, which is [1 0 0]. Last but not least, we can know the largest exposed faces of the crystal belong to high-indexed  $\{1 0 0\}$  planes.<sup>2</sup>

## **References:**

- 1. G. X. Hu, X. Cai, Y. H. Rong, *Fundamentals of Materials Science*, 2nd Ed., China, Shanghai Jiao Tong University Press Co., Ltd, 2006, 19-35.
- 2. F. R. Zhou, P. L. Zhu, X. Z. Fu, R. Q. Chen, R. Sun and C. P. Wong, CrystEngComm, 2014, 16, 766-774.